

Fig.1 – Fabrication Steps

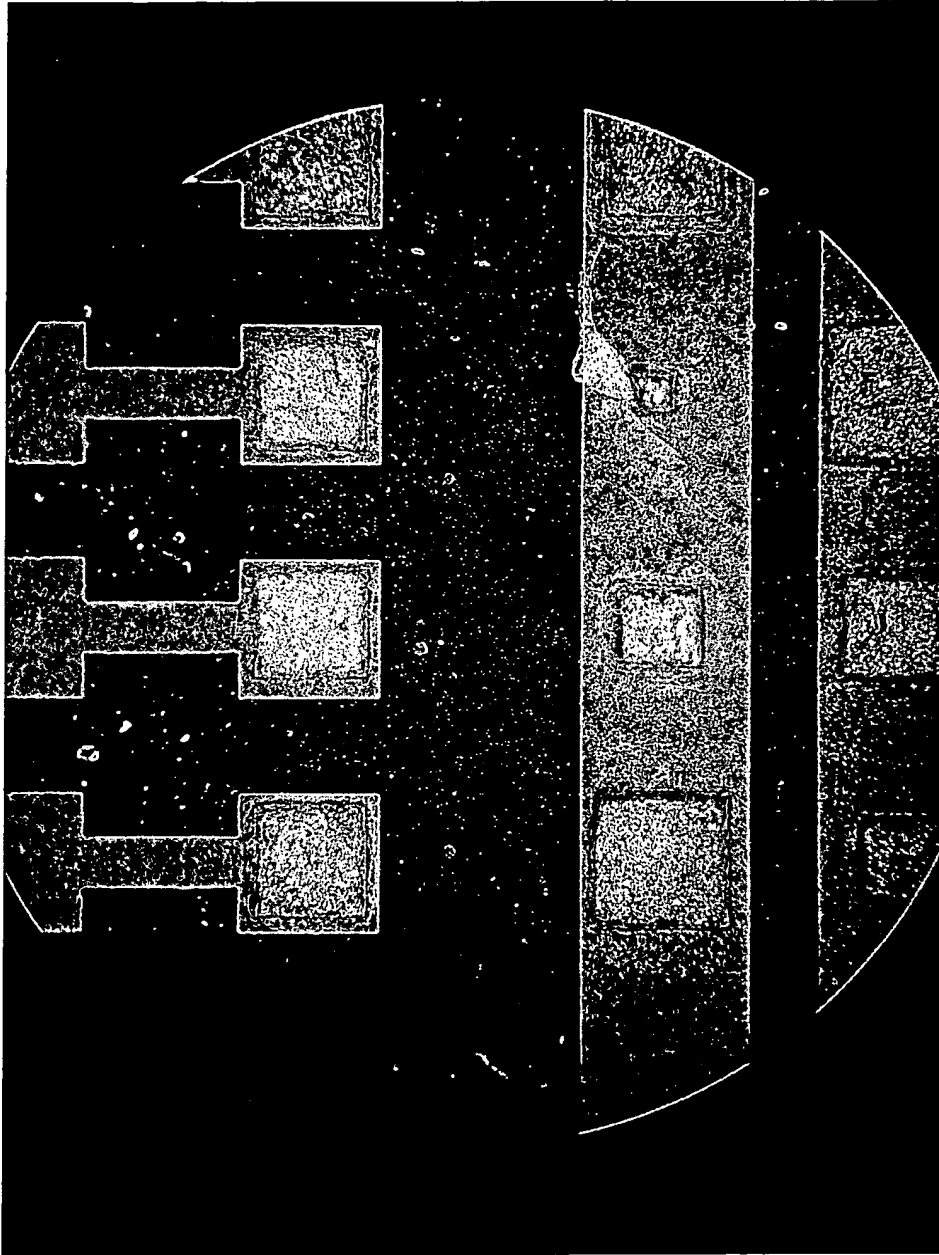


Fig. 2 – Polymer Bumps Under Optical Microscope

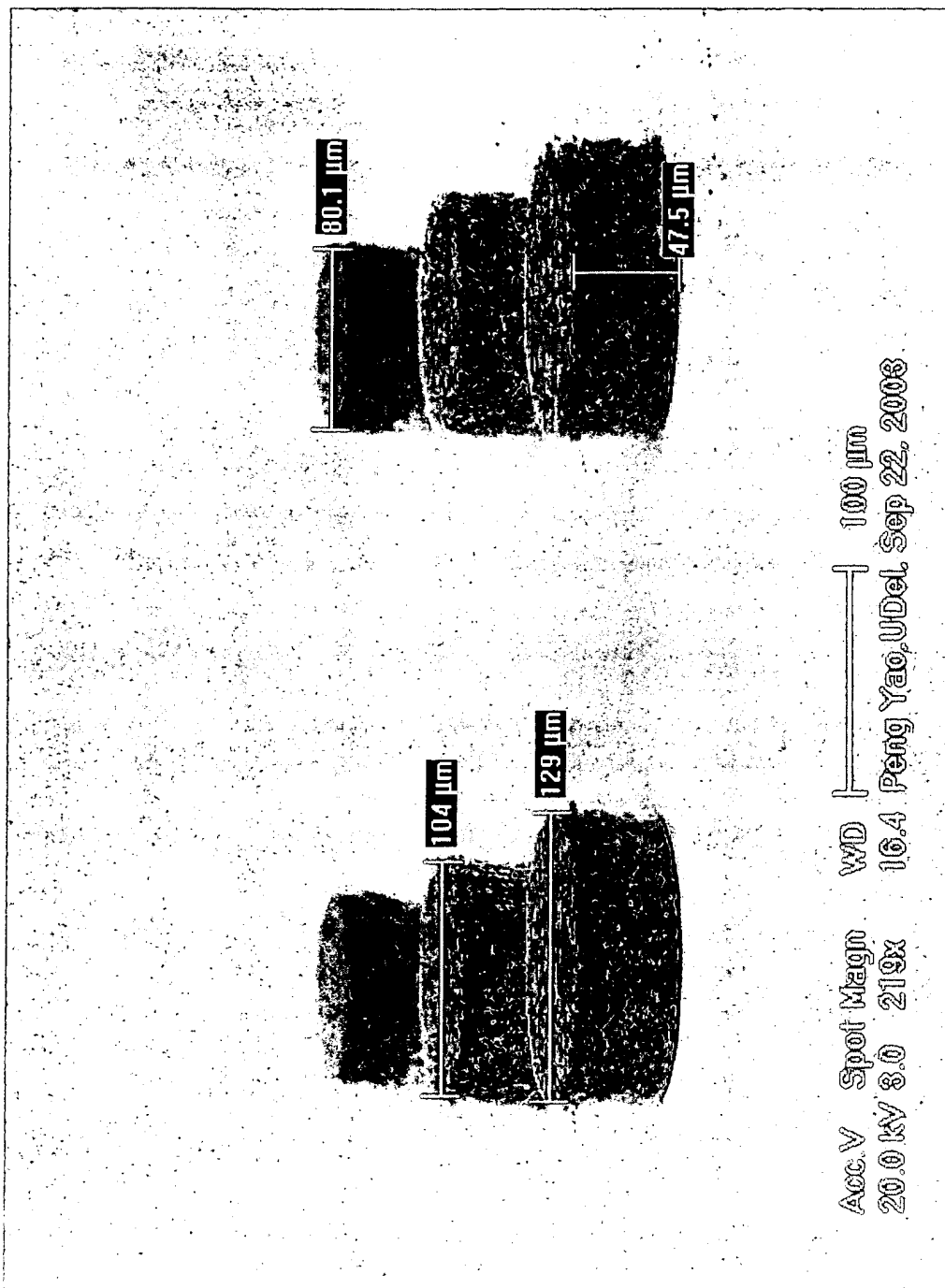


Fig. 3 - SEM View of Surface of Polished Polymer Bumps

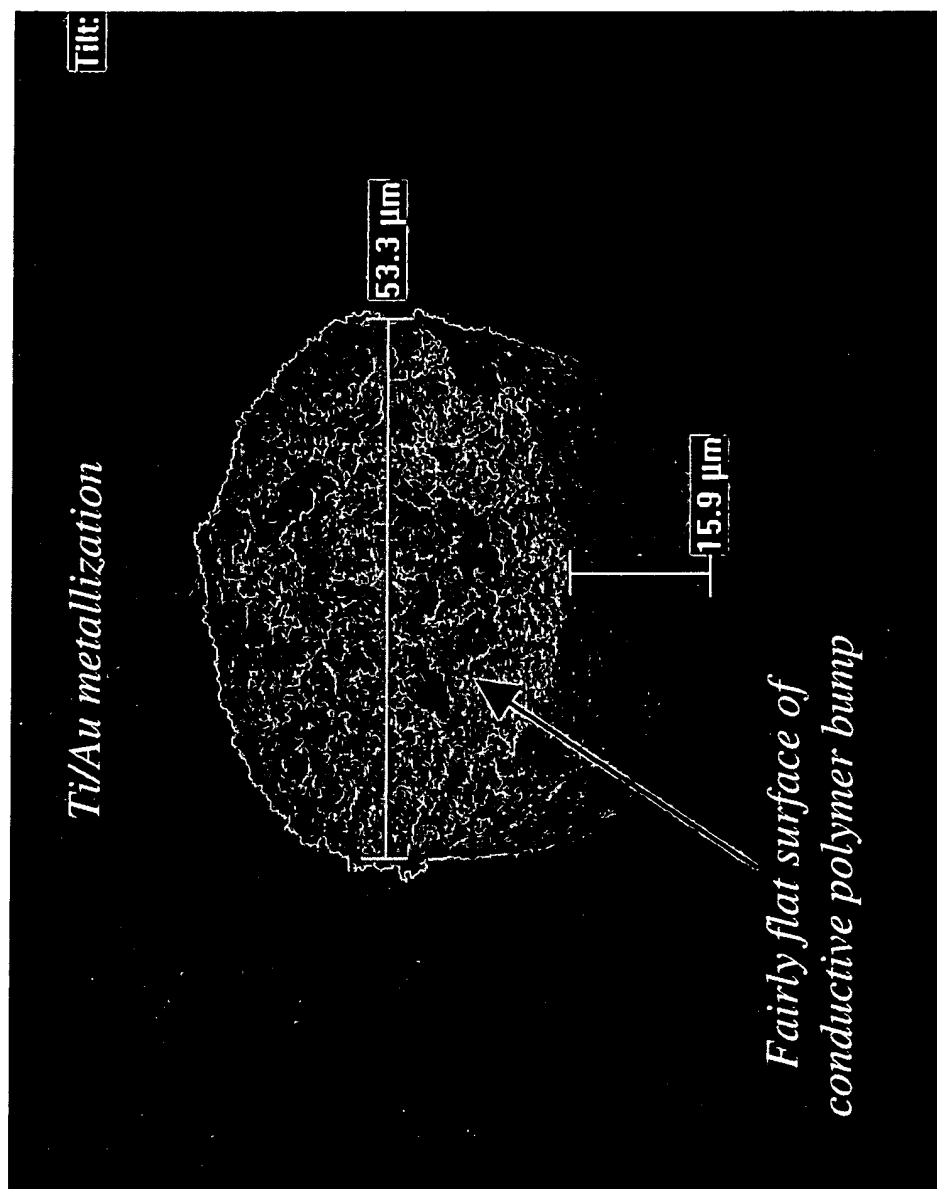


Fig. 4 - SEM View of Surface of Polished Conductive Polymer Bumps

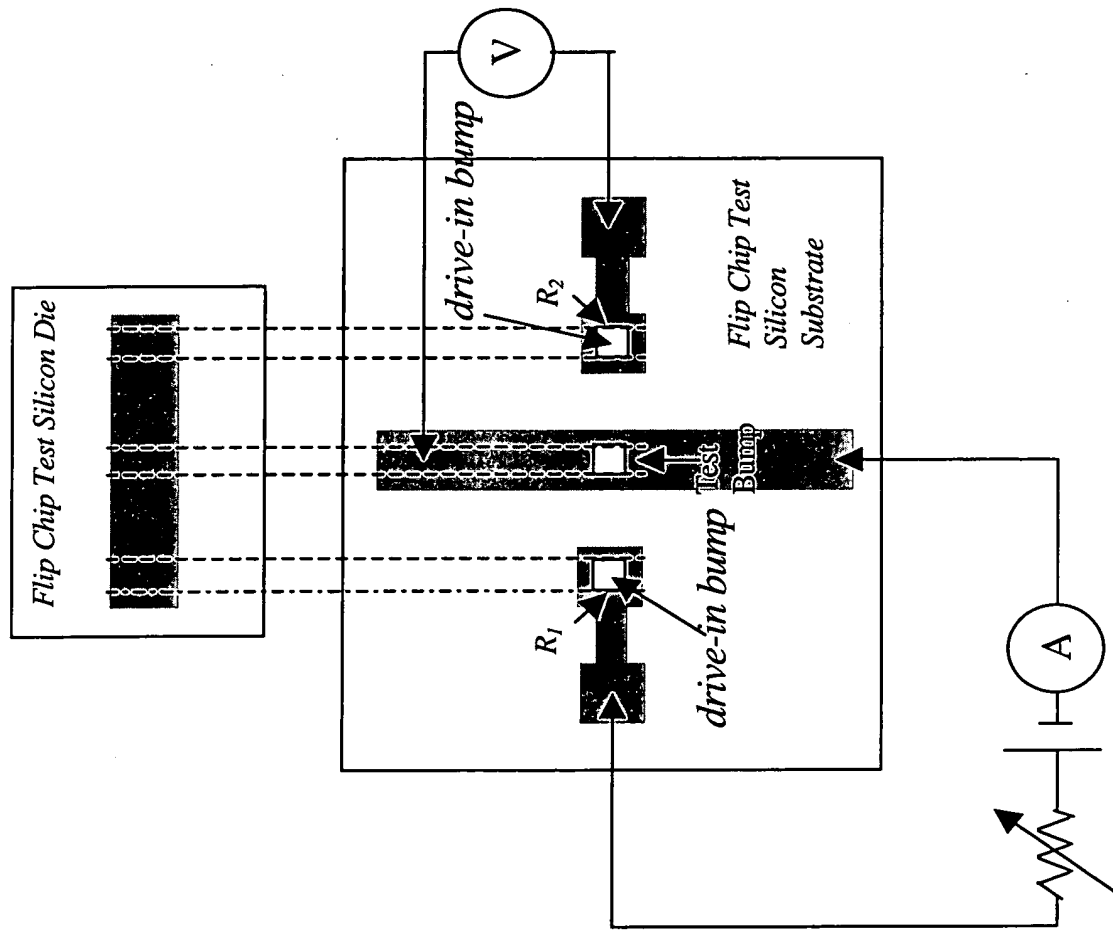


Fig. 5 - Contact Resistance Test Setup

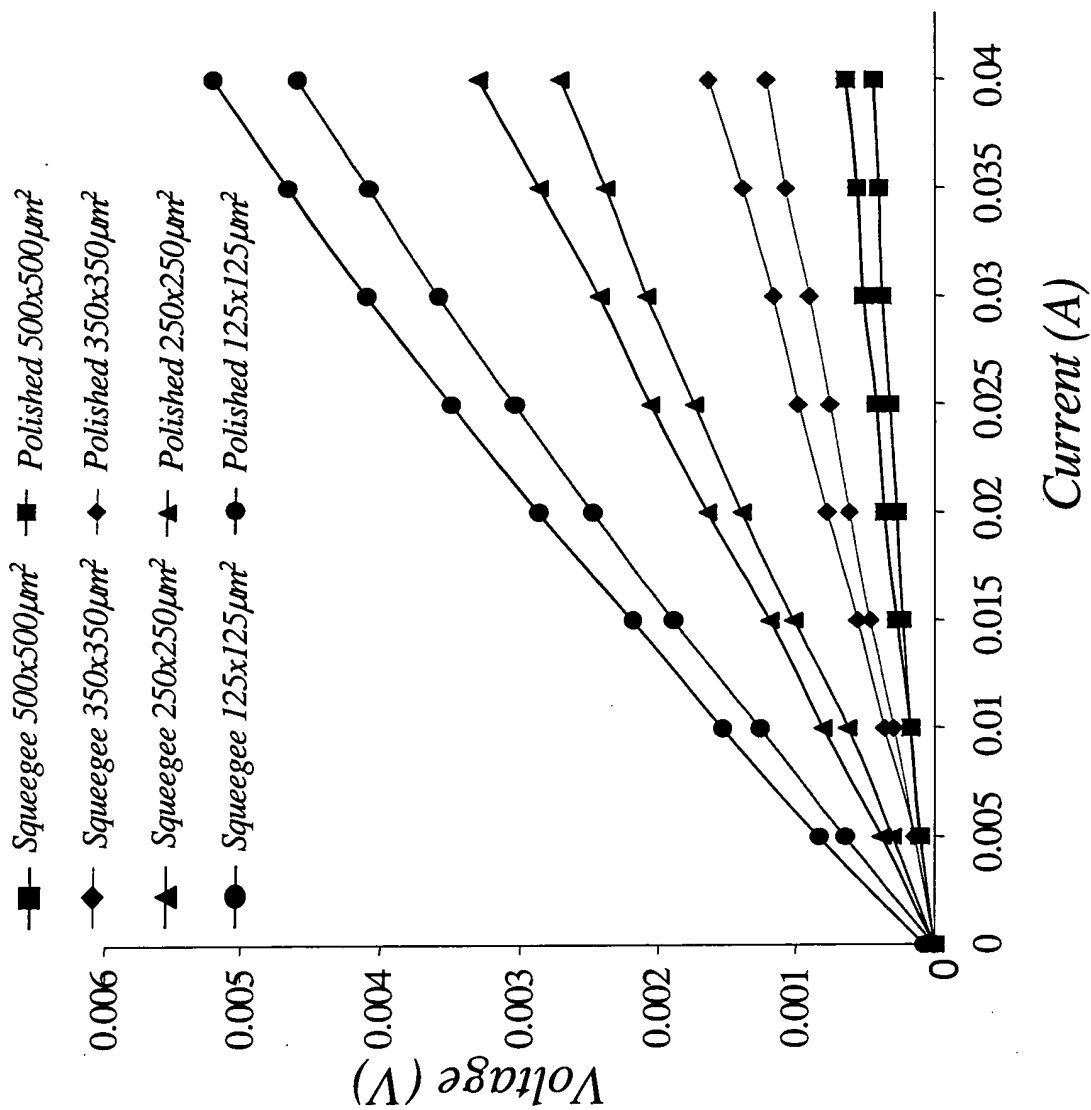


Fig. 6 - Contact Resistance Comparison

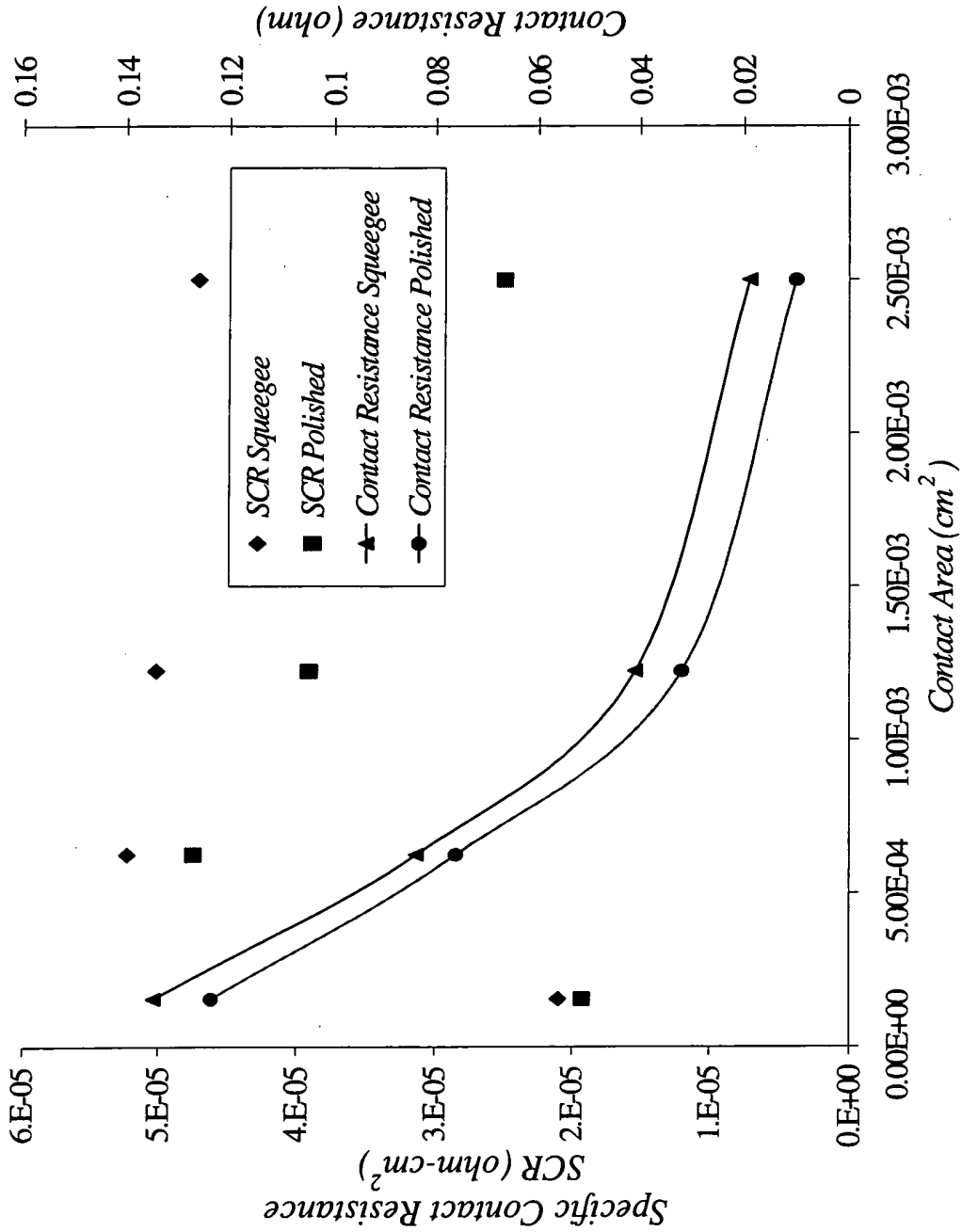


Fig. 7 - Contact Resistance and Specific Contact Resistance

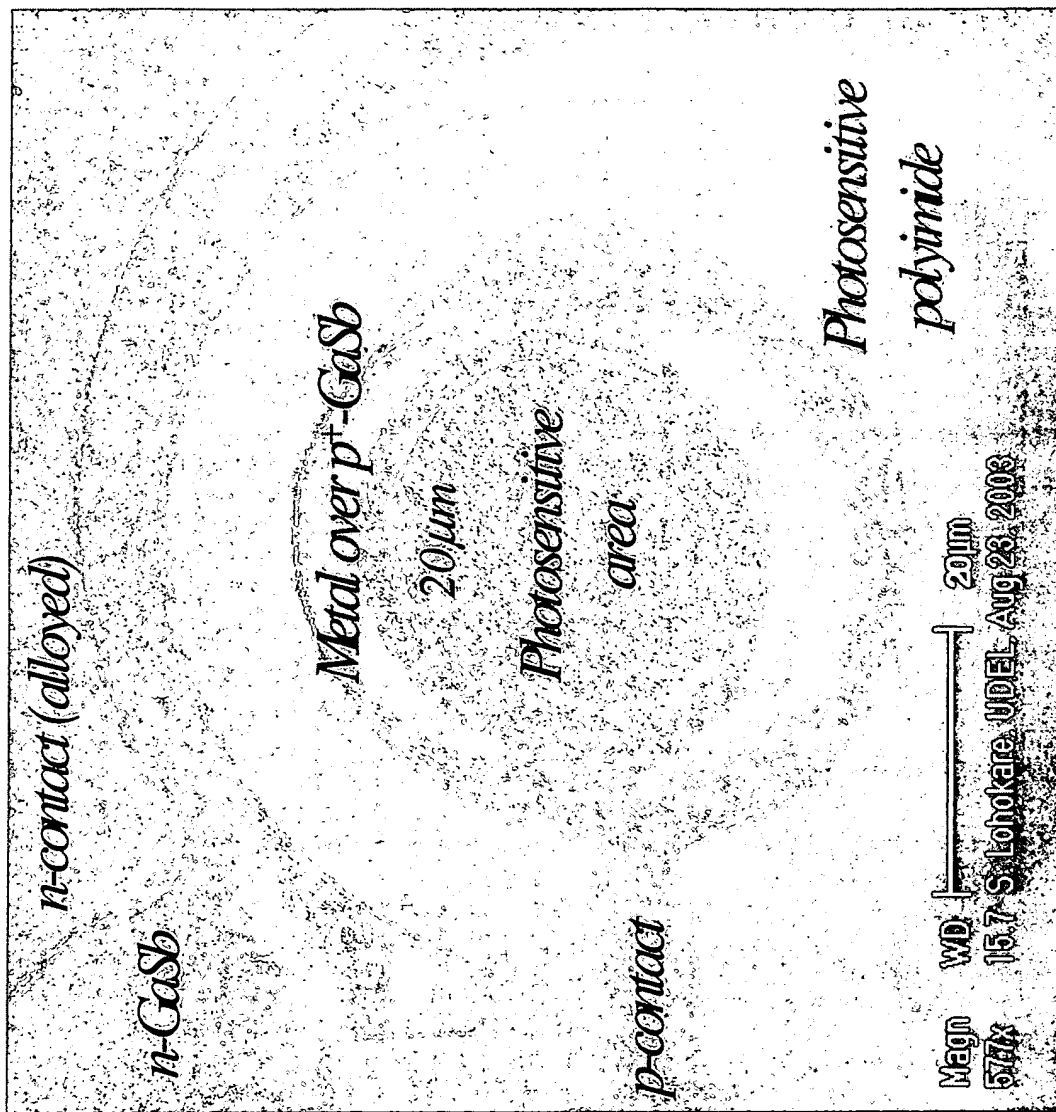


Fig. 8 – SEM View of AlGaAsSb/AlGaSb p-i-n Photodetector

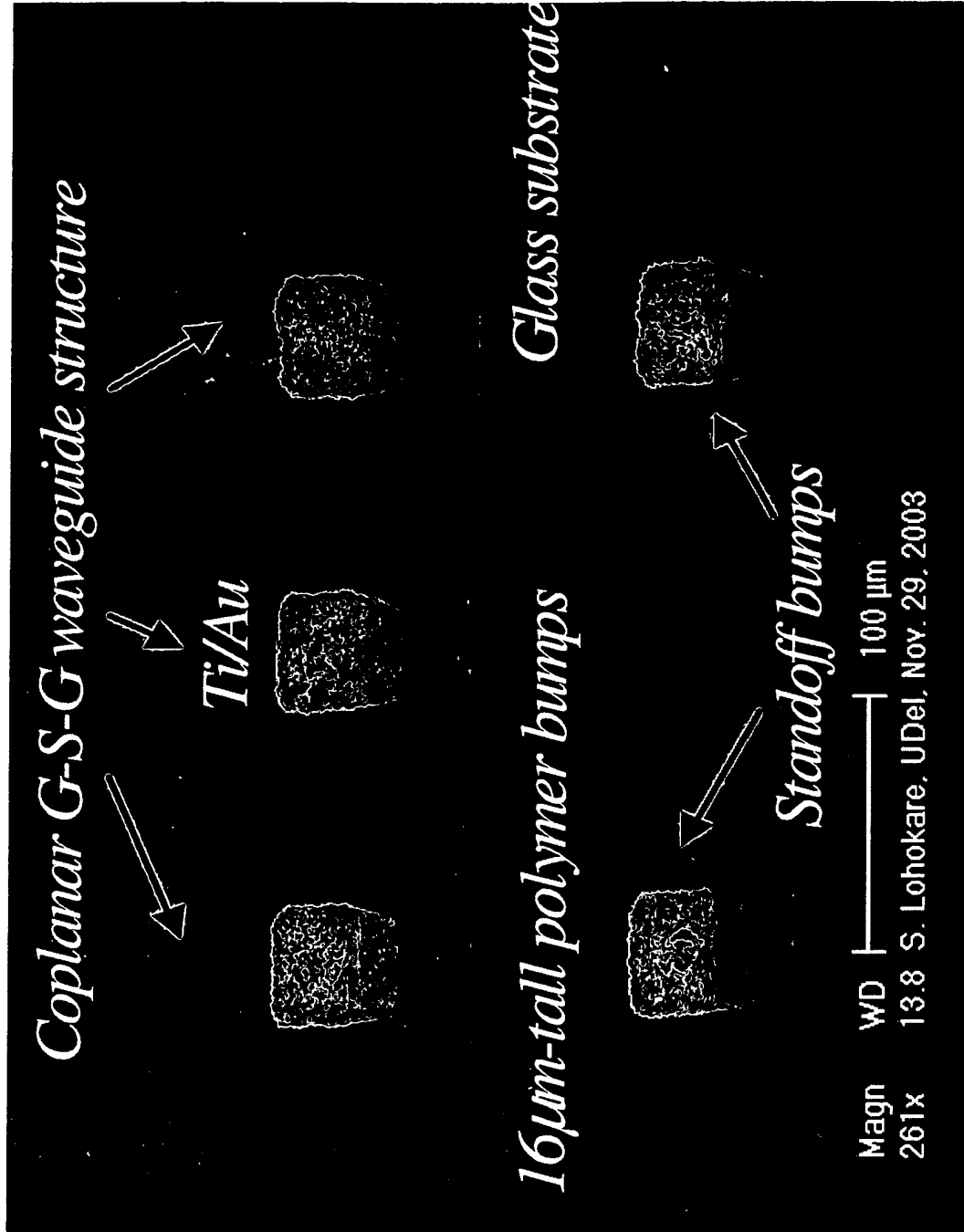


Fig. 9 – SEM View of Conductive Adhesive Bumps on Coplanar Waveguide

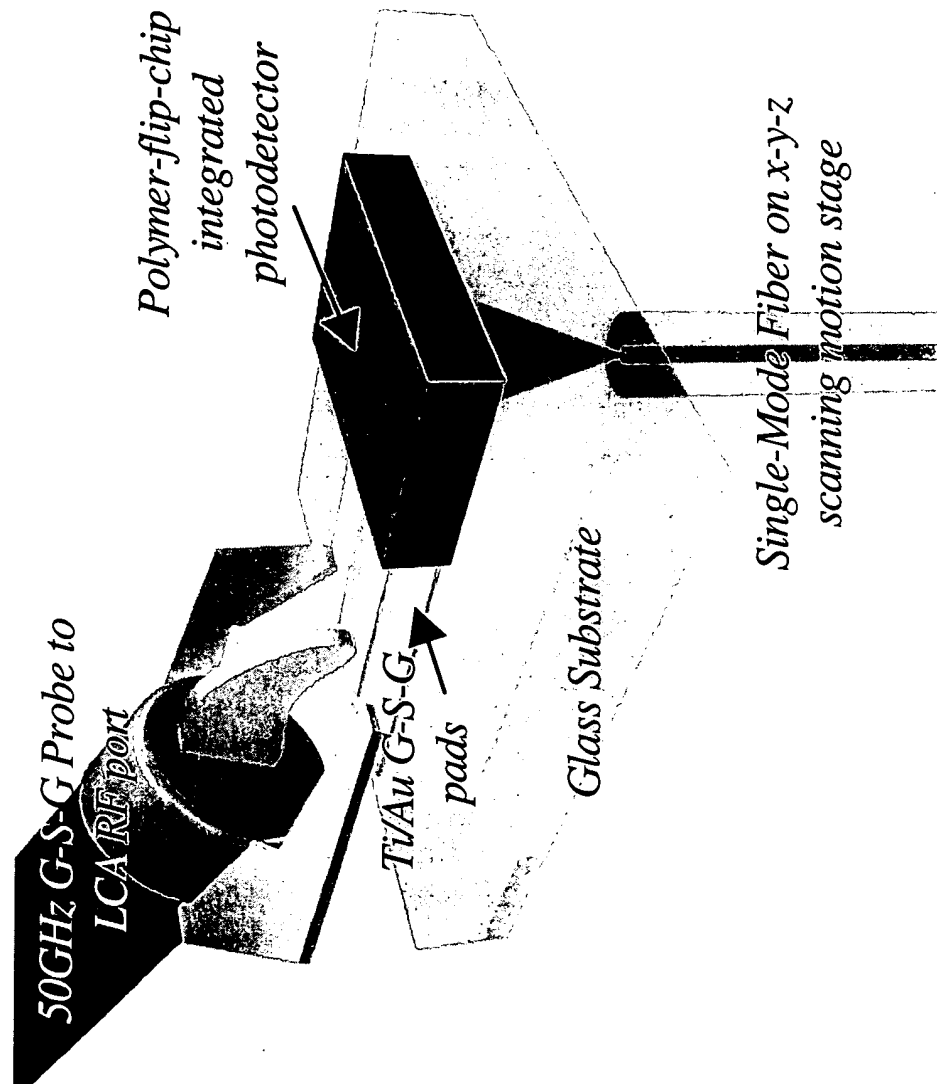


Fig. 10 – Schematic of Test Setup for PFC Integrated $p-i-n$ Detector

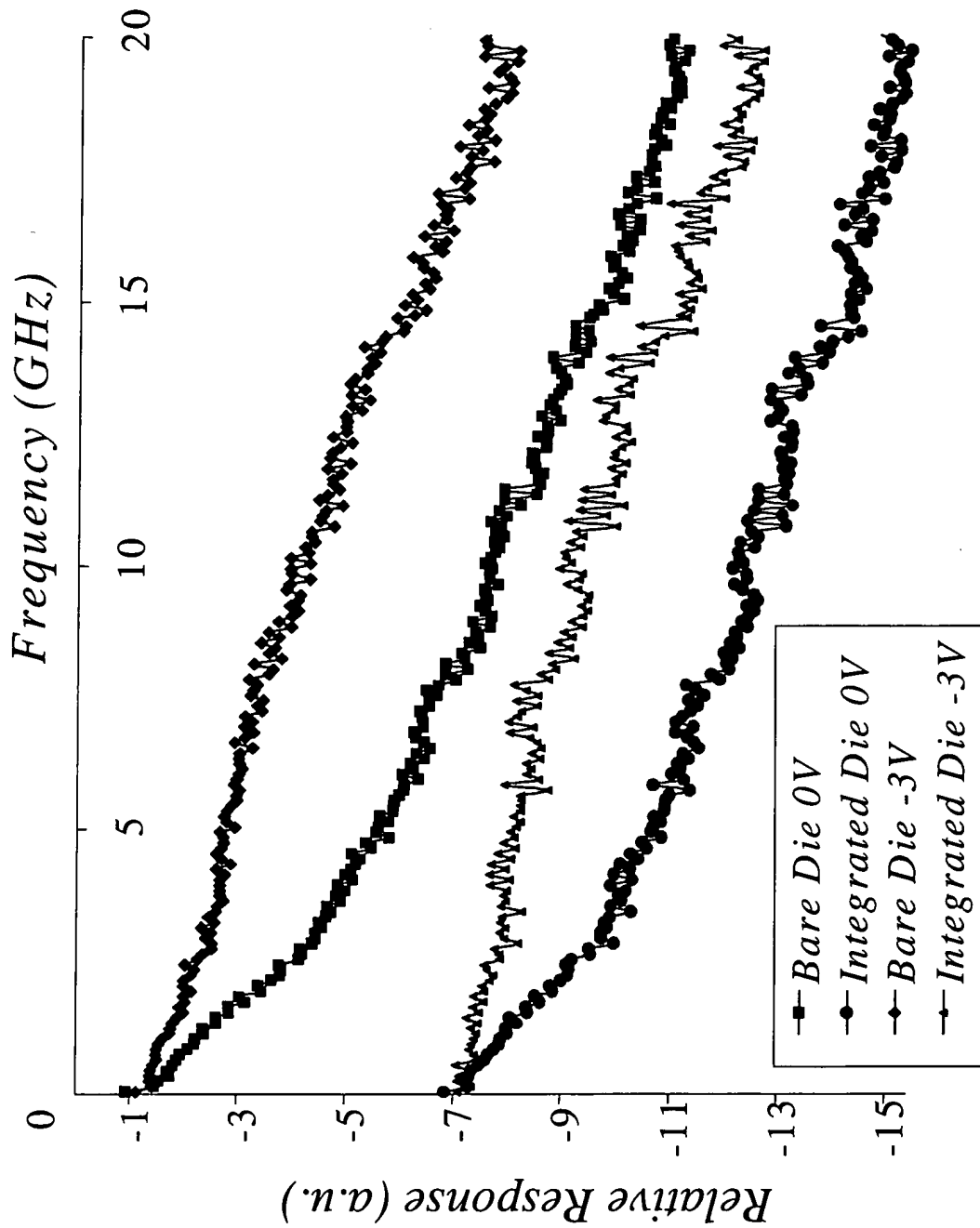


Fig. 11 – Normalized BW Response for Bare-Die and PFC Integrated *p-i-n* Detector

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